

Notice of References Cited	Application/Control No. 10/577,690		Applicant(s)/Patent Under Reexamination AVENELL, ERIC GWYN	
	Examiner GLORIA R. WEEKS		Art Unit 3721	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0285458	12-2005	Moeleker et al.	310/057
*	B	US-2005/0156470	07-2005	Gromoll et al.	310/052
*	C	US-2005/0134125	06-2005	Kim, In Chan	310/058
*	D	US-2004/0113500	06-2004	Casey et al.	310/058
*	E	US-7,462,963	12-2008	Ishihara et al.	310/58
*	F	US-6,528,919	03-2003	Fujii et al.	310/88
*	G	US-6,472,779	10-2002	Hwang et al.	310/12.29
*	H	US-6,155,802	12-2000	Choi et al.	417/366
*	I	US-6,078,115	06-2000	Uchida et al.	310/58
*	J	US-6,037,724	03-2000	Buss et al.	318/71
*	K	US-5,770,899	06-1998	Hayashi, Yutaka	310/12.06
*	L	US-4,922,146	05-1990	Vanduyn, Martin	310/59
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	I					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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